



FLIP CHIP MODULES TEST DATA

TYPE: R 401
CLOCK

TEST	CONDITIONS	MAXIMUM	MINIMUM
FREQUENCY RANGE NO LOAD	RANGE L	2.3 MS	70 MS
	RANGE M	.2 MS	3.4 MS
	RANGE N	19 μS	360 μS
	RANGE P	2.4 μS	34 μS
	RANGE R	.3 μS	3.3 μS
% CHANGE OF PER. SET PERIOD AT 0.5 MS AT -15V	% CHANGE AS -15V IS VARIED	-18V	+0.7 %
		-12V	-0.3 %
% CHANGE OF PER. SET PERIOD AT 500 NS AT -15V	% CHANGE AS -15V IS VARIED	-18V	+1.8 %
		-12V	-0.2 %
JITTER TEST SET PERIOD TO 0.5 MS AT -15 V	VARY -15V	-12V	.2 %
		-15V	.2 %
		-18V	.2 %
ENABLE GATE TTT SET ENABLE RATE 500 KC	SET CLOCK PER. TO 500 NS	30 NS	
PULSE AMPLITUDE SET PERIOD TO 500 NS.	NO LOAD	3.7 V	
	750 Ω TO -15V		3.7 V
PULSE WIDTH 500 NS PERIOD	NO LOAD	135 NS	
	750 Ω TO -15V		135 NS
LOWEST FREQUENCY	NO LOAD	3.6 V	
	750 Ω TO -15V		3.6 V
FREQUENCY	NO LOAD	130 NS	
	750 Ω TO -15V		130 NS

TECHNICAL INFORMATION

Instruction literature and technical bulletins are available on all digital products, if you would like to be added to our mailing list for this type of material or if you have any questions about the equipment you have purchased, please contact the nearest Digital Sales Office.

MAINTENANCE INFORMATION

Repair of printed circuitry should be done with a low voltage, fairly cool soldering iron to prevent damage to the transistors and keep the copper from lifting. Oscilloscopes used to troubleshoot a module or system should be grounded to prevent damaging transients.

ELEC. TESTER:



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